AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings of claims in the application:

LISTING OF CLAIMS:

1. (currently amended) An ion implantation method, characterized in that wherein the method comprises the steps of:

generating continuously, by plasma generation means, plasma at least including implantation target—ions and charged particles of a polarity opposite to that of the implantation target—ions;

transporting the plasma onto a <u>deposition deposition assistance</u> substrate under an influence of a magnetic field, wherein the direction of the applied magnetic field is from the plasma generation means to the deposition substrate;

giving acceleration energies to the implantation $\frac{\text{target}}{\text{tons}}$ ions by a $\frac{\text{DC}}{\text{bias}}$ voltage applied $\frac{\text{by}}{\text{to}}$ the $\frac{\text{deposition}}{\text{deposition}}$

irradiating the plasma toward the $\underline{\text{deposition}}$ $\underline{\text{deposition assistance}}$ substrate; and

implanting the implantation target—ions into a material film on the deposition deposition—assistance—substrate.

- 2. (currently amended) The ion implantation method of claim 1, characterized in that wherein the bias voltage has a polarity opposite to that of the implantation target ions.
- 3. (currently amended) The ion implantation method of claim 1, characterized in that wherein the plasma is irradiated to the material film deposited on the deposition deposition assistance—substrate, to implant the implantation target—ions into the material film.
- 4. (currently amended) The ion implantation method of claim 1, characterized in that wherein the plasma is irradiated toward the deposition deposition—assistance—substrate simultaneously with deposition of the material film onto the deposition deposition assistance—substrate, to implant the implantation target—ions into the material film.
- 5. (currently amended) The ion implantation method of claim 1, characterized in that wherein the implantation target ions are implanted into the material film by repeating the following steps:

a step of depositing a material film on the $\underline{\text{deposition}}$ $\underline{\text{deposition}}$ assistance—substrate; and

the step of irradiating the plasma toward the deposition deposition—assistance—substrate.

- 6. (currently amended) The ion implantation method of claim 1, characterized in that wherein the ions are implanted into the material film comprising fullerene—to produce containing-fullerene or hetero-fullerene within the material film.
- 7. (currently amended) The ion implantation method of claim 6, characterized in that wherein the acceleration energies are within a range of 10 eV inclusive to 500 eV inclusive.
- 8. (currently amended) The ion implantation method of claim 6, characterized in that wherein the acceleration energies are within a range of 20 eV inclusive to 500 eV inclusive.
- 9. (currently amended) The ion implantation method of claim 1, characterized in that wherein the material film is carbon nanotube, a material film is an of organic—EL electroluminescent material, a material film of solar cell, a material film of fuel cell, an organic semiconductor material film, or an electroconductive polymer material film.
- 10. (currently amended) The ion implantation method of claim 9, characterized in that wherein the acceleration energies are within a range of 0.5 eV inclusive to 500 eV inclusive.

- 11. (currently amended) The ion implantation method of claim 1, characterized in that wherein the implantation target ions have an ionic current density of 1 $\mu A/cm^2$ or more.
- 12. (currently amended) The ion implantation method of claim 1, characterized in that wherein the implantation target ions are implanted, by arranging a grid electrode in the plasma and separatedly from the deposition deposition assistance substrate to thereby control a plasma potential by a voltage applied to the grid electrode.
- 13. (currently amended) The ion implantation method of claim 12, characterized in that wherein the grid electrode is located at a distance in a range of 1 mm inclusive to 50 mm inclusive from the deposition deposition assistance—substrate.
- 14. (currently amended) The ion implantation method of claim 1, characterized in that wherein the implantation target ions are implanted, by providing the deposition deposition—assistance—substrate in a form of a plurality of divisional deposition deposition oriented—plates in—having concentric circle shapes, and by independently controlling bias voltages applied to the plurality of deposition deposition deposition oriented—plates.

- 15. (currently amended) The ion implantation method of claim 8, <u>upon</u> the implantation <u>target</u>ions <u>being are</u>-implanted, <u>further comprising by</u> cooling the <u>deposition deposition</u> assistance—substrate by cooling means.
- 16. (currently amended) An ion implantation apparatus comprising:

a vacuum vessel;

plasma generation means for generating <u>continuously</u> plasma at least including implantation target ions and charged particles of a polarity opposite to that of the implantation target ions, within said vacuum vessel;

magnetic field generating means, wherein the direction of the applied magnetic field is from the plasma generation means to the deposition substrate;

a <u>deposition_deposition_assistance_</u>substrate arranged within said vacuum vessel;

bias voltage application means for applying a <u>DC</u> bias voltage to said <u>deposition deposition assistance</u> substrate; and material film deposition means for depositing a material film onto said <u>deposition deposition assistance</u> substrate.

17. (currently amended) An ion implantation apparatus comprising:

a vacuum vessel;

plasma generation means for generating <u>continuously</u> plasma at least including implantation target ions and charged particles of a polarity opposite to that of the implantation target ions, within said vacuum vessel;

magnetic field generating means, wherein the direction of the applied magnetic field is from the plasma generation means to the deposition substrate;

a <u>deposition_deposition_assistance_substrate arranged</u> within said vacuum vessel; and

bias voltage application means for applying a $\underline{\tt DC}$ bias voltage to said deposition $\underline{\tt deposition-assistance}$ substrate.

- 18. (currently amended) The ion implantation apparatus of claim 16, characterized in that wherein said deposition deposition—assistance—substrate comprises—conveyed via a conveyor or rotary cylinder.
- of claim 16, characterized in that wherein said apparatus includes a transport device comprising a belt conveyor or rotary cylinder, and

that said transport device is configured to support and transport a plurality of said <u>deposition deposition assistance</u> substrate within said vacuum device.

- 20. (currently amended) The ion implantation apparatus of claim 19, characterized in that wherein said deposition deposition assistance—substrates are each supported to said transport device by an electroconductive clamp member.
- 21. (currently amended) The ion implantation apparatus of claim 17, characterized in that wherein said ion implantation apparatus further comprises cooling means for cooling said deposition deposition assistance—substrate.